Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10516625	MIYANO ET AL.	
Examiner	Art Unit	
Le. Hien	3662	

SEARCHED				
Class	Subclass	Date	Examiner	
Inventor's		12/8/2006		
Name Search	<u> </u>			
Plus Search		12/8/2006		
NPL Search		12/11/2006		
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